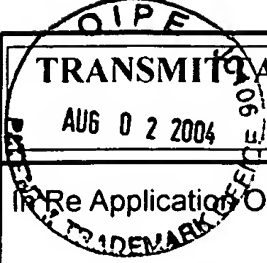
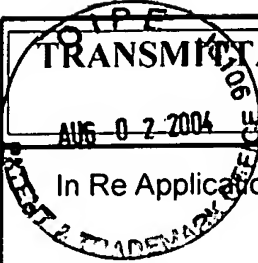
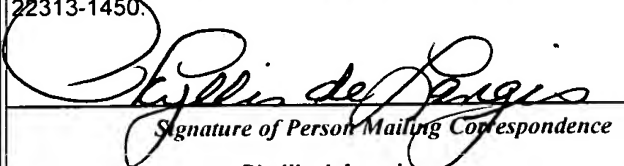
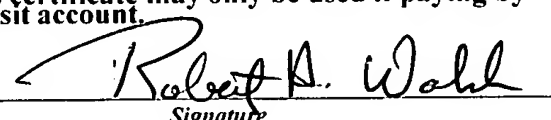


IFW

 TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT (Under 37 CFR 1.97(b) or 1.97(c))				Docket No. BUR920030066US1	
Re Application Of: METHODS AND APPARATUS FOR DEFECT ISOLATION.					
Application No. 10/708380	Filing Date 02/27/04	Examiner Unassigned	Customer No. 024241	Group Art Unit	Confirmation No.
Title: METHODS AND APPARATUS FOR DEFECT ISOLATION.					
<p style="text-align: center;">Address to: Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450</p> <p style="text-align: center;">37 CFR 1.97(b)</p> <p>1. <input checked="" type="checkbox"/> The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.</p> <p style="text-align: center;">37 CFR 1.97(c)</p> <p>2. <input type="checkbox"/> The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:</p> <p style="padding-left: 40px;"><input type="checkbox"/> the statement specified in 37 CFR 1.97(e);</p> <p style="text-align: center;">OR</p> <p style="padding-left: 40px;"><input type="checkbox"/> the fee set forth in 37 CFR 1.17(p).</p>					

<div style="float: left; width: 150px; text-align: center;">  </div> <div style="float: right; width: 400px;"> TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT (Under 37 CFR 1.97(b) or 1.97(c)) </div>					Docket No. BUR920030066US1	
In Re Application: METHODS AND APPARATUS FOR DEFECT ISOLATION.						
Application No.	Filing Date	Examiner	Customer No.	Group Art Unit	Confirmation No.	
10/708380	02/27/04	Unassigned	024241			
METHODS AND APPARATUS FOR DEFECT ISOLATION.						
Payment of Fee (Only complete if Applicant elects to pay the fee set forth in 37 CFR 1.17(p))						
<input type="checkbox"/> A check in the amount of _____ is attached.						
<input checked="" type="checkbox"/> The Director is hereby authorized to charge and credit Deposit Account No. 09-0456						
as described below.						
<input checked="" type="checkbox"/> Charge the amount of _____						
<input checked="" type="checkbox"/> Credit any overpayment.						
<input checked="" type="checkbox"/> Charge any additional fee required.						
Certificate of Transmission by Facsimile* <div style="border: 1px solid black; padding: 5px; margin-top: 5px;"> I certify that this document and authorization to charge deposit account is being facsimile transmitted to the United States Patent and Trademark Office (Fax. No. _____) </div> <div style="border: 1px solid black; padding: 5px; margin-top: 5px;"> _____ (Date) </div> <div style="border: 1px solid black; padding: 5px; margin-top: 5px;"> _____ Signature </div> <div style="border: 1px solid black; padding: 5px; margin-top: 5px;"> _____ Typed or Printed Name of Person Signing Certificate </div>				Certificate of Mailing by First Class Mail <div style="border: 1px solid black; padding: 5px; margin-top: 5px;"> I certify that this document and fee is being deposited on 7-29-04 with the U.S. Postal Service as first class mail under 37 C.F.R. 1.8 and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450. </div> <div style="border: 1px solid black; padding: 5px; margin-top: 5px;">  Signature of Person Mailing Correspondence Phyllis deLangis </div> <div style="border: 1px solid black; padding: 5px; margin-top: 5px;"> _____ Typed or Printed Name of Person Mailing Certificate </div>		
<div style="display: flex; justify-content: space-between;"> <div style="width: 45%;"> <p>*This certificate may only be used if paying by deposit account.</p> <div style="text-align: center;">  _____ Signature </div> </div> <div style="width: 45%;"> <p>Dated: 7/28/2004</p> </div> </div>						
Robert A. Walsh, Esq. Reg. No.: 26,516 I P Law Department IBM Corporation 1000 River Street - 972E Essex Junction, VT 05452 CC:						

Express Mail Label No.:

PATENTS

Docket No. BUR920030066US1



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Leendert M. Huisman, William V. Huott
and Franko Motika

Serial No. : 10/708,380

Filed : February 27, 2004

For : METHODS AND APPARATUS FOR DEFECT
ISOLATION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.56 and 1.97,
applicants wish to call the attention of the Examiner to the
following references:

E.B. Eichelberger, et al., "A Logic Design
Structure for LSI Testability", Proceedings of the
Fourteenth Design Automation Conference, New Orleans, 1977,
pps. 462-468.

David P. Vallett, "IC Failure Analysis: The
Importance of Test and Diagnostics", IEEE Design & Test of
Computers, July-September 1997, pps. 76-82.

James L. Schafer et al., "Partner SRLS for Improved Shift Register Diagnostics", IEEE VLSI Test Symposium, June 1992, pps. 198-200.

Sandip Jundu, "Diagnosing Scan Chain Faults", IEEE Transactions On Very Large Scale Integration (VLSI) Systems, Vol. 2, No. 4, December 1994, pps. 512-517.

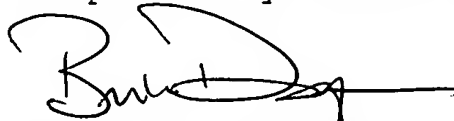
Samantha Edirisooriya et al., "Diagnosis of Scan Path Failures", Proceedings of IEEE VLSI Test Symposium April 1995, pps. 250-255.

Sridhar Narayanan et al., "An Efficient Scheme to Diagnose Scan Chains", International Test Conference, July 1997, pps. 704-713.

These references also are listed on the accompanying Information Disclosure Statement (Form PTO-1449). The submission of this Information Disclosure Statement shall not be construed as a representation that a search has been made or that no other art than that identified above exists.

Consideration of the foregoing in relation to this
patent application is respectfully requested.

Respectfully Submitted,

A handwritten signature in black ink, appearing to read 'Brian Dugan', with a stylized flourish extending to the right.

Brian M. Dugan, Esq.
Registration No. 41,720
Dugan & Dugan, PC
Attorneys for Applicants
(914) 332-9081

Dated: June 16, 2004
Tarrytown, New York

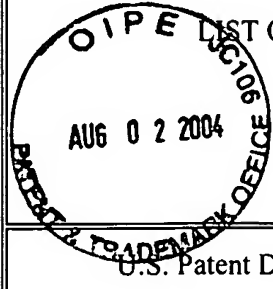
U.S. Department of Commerce, Patent and Trademark Office

Docket No.:

BUR920030066US1

Serial No.:

10/708,380



LIST OF RELEVANT ART CITED BY APPLICANT

(Use several sheets if necessary)

Applicant(s):

Leendert M. Huisman et al.

Filing Date:

February 27, 2004

Group:

unknown

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

Foreign Patent Documents

Translation

		Document Number	Date	Country	Class	Subclass	Yes	No
	AG							
	AH							
	AI							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AJ	E.B. Eichelberger, et al, "A Logic Design Structure for LSI Testability", Proceedings of the Fourteenth Design Automation Conference, New Orleans, 1977, pps. 462-468.
AK	David P. Vallett, "IC Failure Analysis: The Importance of Test and Diagnostics", IEEE Design & Test of Computers, July-September 1997, pps. 76-82.
AL	James L. Schafer et al. "Partner SRLS for Improved Shift Register Diagnostics", IEEE VLSI Test Symposium, June 1992, pps. 198-200.
AM	Sandip Jundu, "Diagnosing Scan Chain Faults", IEEE Transactions On Very Large Scale Integration (VLSI) Systems, Vol. 2, No. 4, December 1994, pps. 512-517.
AN	Samantha Edirisooriya et al., "Diagnosis of Scan Path Failures", Proceedings of IEEE VLSI Test Symposium April 1995, pps. 250-255.
AO	Sridhar Narayanan et al., "An Efficient Scheme to Diagnose Scan Chains", International Test Conference, July 1997, pps. 704-713.

Examiner	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.